

<b>Notice of References Cited</b>	Application/Control No. 10/799,328	Applicant(s)/Patent Under Reexamination ALLEN ET AL.	
	Examiner Ryan Lepisto	Art Unit 2883	Page 1 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,424,781	07-2002	Puetz et al.	385/135
	B	US-5,640,482	06-1997	Barry et al.	385/135
	C	US-5,758,003	05-1998	Wheeler et al.	385/134
	D	US-5,758,002	05-1998	Walters, Mark D.	385/134
	E	US-5,825,962	10-1998	Walters et al.	385/135
	F	US-5,913,006	06-1999	Summach, Harley Robert William	385/134
	G	US-6,044,193	03-2000	Szentesi et al.	385/134
	H	US-6,160,946	12-2000	Thompson et al.	385/134
	I	US-6,181,862	01-2001	Noble et al.	385/135
	J	US-6,195,494	02-2001	Abbott et al.	385/134
	K	US-6,201,919	03-2001	Puetz et al.	385/134
	L	US-6,256,444	07-2001	Bechamps et al.	385/134
	M	US-6,278,829	08-2001	BuAbbud et al.	385/135

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1160603 A1	12-2001	European Patent	VAN, OVERMEIR PETER	G02B 06/44
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/799,328	Applicant(s)/Patent Under Reexamination ALLEN ET AL.	
	Examiner Ryan Lepisto	Art Unit 2883	Page 2 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,289,159	09-2001	Van Hees et al.	385/134
	B	US-6,362,422	03-2002	Vavrik et al.	174/50
	C	US-6,398,149	06-2002	Hines et al.	242/399
	D	US-6,418,262	07-2002	Puetz et al.	385/134
	E	US-6,438,311	08-2002	Zarnowitz, Arthur	385/135
	F	US-2002/0118943	08-2002	Solheid et al.	385/134
	G	US-6,468,112	10-2002	Follingstad et al.	439/719
	H	US-6,467,633	10-2002	Mendoza, Jose-Filonel Tawag	211/26
	I	US-6,487,356	11-2002	Harrison et al.	385/135
	J	US-2002/0176681	11-2002	Puetz et al.	385/134
	K	US-6,501,899	12-2002	Marrs et al.	385/135
	L	US-6,532,332	03-2003	Solheid et al.	385/134
	M	US-6,535,682	03-2003	Puetz et al.	385/135

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/799,328	Applicant(s)/Patent Under Reexamination ALLEN ET AL.	
	Examiner Ryan Lepisto	Art Unit 2883	Page 3 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,556,763	04-2003	Puetz et al.	385/135
	B	US-2003/0095772	05-2003	Solheid et al.	385/134
	C	US-6,571,047	05-2003	Yarkosky et al.	385/135
	D	US-6,584,267	06-2003	Caveney et al.	385/134
	E	US-6,591,051	07-2003	Solheid et al.	385/134
	F	US-6,614,978	09-2003	Caveney, Jack E.	385/135
	G	US-2003/0185535	10-2003	Tinucci et al.	385/134
	H	US-6,633,717	10-2003	Knight et al.	385/135
	I	US-2004/0037533	02-2004	Knudsen, Clinton M.	385/135
	J	US-6,711,339	03-2004	Puetz et al.	385/135
	K	US-6,760,531	07-2004	Solheid et al.	385/135
	L	US-6,792,191	09-2004	Clapp et al.	385/135
	M	US-6,796,437	09-2004	Krampotich et al.	211/26

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/799,328	Applicant(s)/Patent Under Reexamination ALLEN ET AL.	
	Examiner Ryan Lepisto	Art Unit 2883	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,850,685	02-2005	Tinucci et al.	385/134
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.